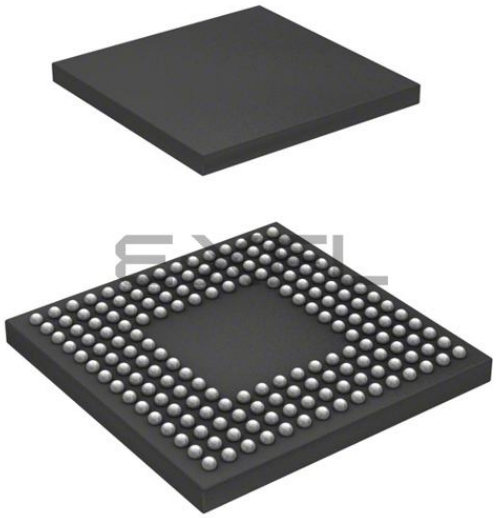
Renesas Electronics America Inc - R7FS7G27H2A01CBG#AC0 Datasheet



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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	240MHz
Connectivity	CANbus, EBI/EMI, Ethernet, I²C, IrDA, MMC/SD, QSPI, SCI, SPI, SSI, UART/USART, USB
Peripherals	DMA, LCD, LVD, POR, PWM, WDT
Number of I/O	126
Program Memory Size	4MB (4M x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	640K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 3.6V
Data Converters	A/D 21x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	176-LFBGA
Supplier Device Package	176-LFBGA (13x13)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r7fs7g27h2a01cbg-ac0

Table 1.3 System (2/2)

Feature	Functional description
Resets	14 resets: • RES pin reset • Power-on reset • Voltage monitor reset 0 • Voltage monitor reset 1 • Voltage monitor reset 2 • Independent Watchdog Timer reset • Watchdog Timer reset • Deep Software Standby reset • SRAM parity error reset • SRAM DED error reset • Bus master MPU error reset • Bus slave MPU error reset • Stack pointer error reset • Software reset. See section 6, Resets in User's Manual.
Low Voltage Detection (LVD)	The Low Voltage Detection (LVD) function monitors the voltage level input to the VCC pin, and the detection level can be selected in the software program. See section 8, Low Voltage Detection (LVD) in User's Manual.
Clocks	• Main clock oscillator (MOSC) • Sub-clock oscillator (SOSC) • High-speed on-chip oscillator (HOCO) • Middle-speed on-chip oscillator (MOCO) • Low-speed on-chip oscillator (LOCO) • PLL frequency synthesizer • Independent Watchdog Timer (WDT) on-chip oscillator • Clock out supports. See section 9, Clock Generation Circuit in User's Manual.
Clock Frequency Accuracy Measurement Circuit (CAC)	The CAC checks the system clock frequency with a reference clock signal by counting the number of pulses of the system clock to be measured. The reference clock can be provided externally through a CACREF pin or internally from various on-chip oscillators. Event signals can be generated when the clock does not match or measurement ends. This feature is particularly useful in implementing a fail-safe mechanism for home and industrial automation applications. See section 10, Clock Frequency Accuracy Measurement Circuit (CAC) in User's Manual.
Low-power modes	Power consumption can be reduced in multiple ways, including by setting clock dividers, controlling EBCLK output, controlling SDCLK output, stopping modules, selecting power control mode in normal operation, and transitioning to low-power modes. See section 11, Low-Power Modes in User's Manual.
Battery backup function	A battery backup function is provided for partial powering by a battery. The battery-powered area includes the RTC, SOSC, backup memory, and switch between VCC and VBATT. See section 12, Battery Backup Function in User's Manual.
Register write protection	The register write protection function protects important registers from being overwritten because of software errors. See section 13, Register Write Protection in User's Manual.
Memory Protection Unit (MPU)	Two MPUs and a CPU stack pointer monitor functions are provided for memory protection. See section 16, Memory Protection Unit (MPU) in User's Manual.
Watchdog Timer (WDT)	The WDT is a 14-bit down-counter. It can be used to reset the MCU when the counter underflows because the system has run out of control and is unable to refresh the WDT. In addition, a non-maskable interrupt or interrupt can be generated by an underflow. A refresh-permitted period can be set to refresh the counter and be used as the condition for detecting when the system runs out of control. See section 27, Watchdog Timer (WDT) in User's Manual.
Independent Watchdog Timer (IWDT)	The IWDT consists of a 14-bit down-counter that must be serviced periodically to prevent counter underflow. The IWDT provides functionality to reset the MCU or to generate a non-maskable interrupt or interrupt for a timer underflow. Because the timer operates with an independent, dedicated clock source, it is particularly useful in returning the MCU to a known state as a fail safe mechanism when the system runs out of control. The IWDT can be triggered automatically on a reset, underflow, or refresh error, or by a refresh of the count value in the registers. See section 28, Independent Watchdog Timer (IWDT) in User's Manual.

Table 1.9 Communication interfaces (1/2)

Feature	Functional description
Serial Communications Interface (SCI)	The SCI is configurable to five asynchronous and synchronous serial interfaces: • Asynchronous interfaces (UART and Asynchronous Communications Interface Adapter (ACIA)) • 8-bit clock synchronous interface • Simple IIC (master-only) • Simple SPI • Smart card interface. The smart card interface complies with the ISO/IEC 7816-3 standard for electronic signals and transmission protocol. Each SCI has FIFO buffers to enable continuous and full-duplex communication, and the data transfer speed can be configured independently using an on-chip baud rate generator. See section 34, Serial Communications Interface (SCI) in User's Manual.
IrDA Interface (IrDA)	The IrDA interface sends and receives IrDA data communication waveforms in cooperation with the SCI1 based on the IrDA (Infrared Data Association) standard 1.0. See section 35, IrDA Interface in User's Manual.
I^2C Bus Interface (IIC)	The three-channel IIC conforms with and provides a subset of the NXP I^2C bus (Inter-Integrated Circuit bus) interface functions. See section 36, I^2C Bus Interface (IIC) in User's Manual.
Serial Peripheral Interface (SPI)	Two independent SPI channels are capable of high-speed, full-duplex synchronous serial communications with multiple processors and peripheral devices. See section 38, Serial Peripheral Interface (SPI) in User's Manual.
Serial Sound Interface (SSI)	The SSI peripheral provides functionality to interface with digital audio devices for transmitting PCM audio data over a serial bus with the MCU. The SSI supports an audio clock frequency of up to 50 MHz, and can be operated as a slave or master receiver, transmitter, or transceiver to suit various applications. The SSI includes 8-stage FIFO buffers in the receiver and transmitter, and supports interrupts and DMA-driven data reception and transmission. See section 41, Serial Sound Interface (SSI) in User's Manual.
Quad Serial Peripheral Interface (QSPI)	The QSPI is a memory controller for connecting a serial ROM (nonvolatile memory such as a serial flash memory, serial EEPROM, or serial FeRAM) that has an SPI-compatible interface. See section 39, Quad Serial Peripheral Interface (QSPI) in User's Manual.
Controller Area Network (CAN) Module	The CAN module provides functionality to receive and transmit data using a message-based protocol between multiple slaves and masters in electromagnetically-noisy applications. The CAN module complies with the ISO 11898-1 (CAN 2.0A/CAN 2.0B) standard and supports up to 32 mailboxes, which can be configured for transmission or reception in normal mailbox and FIFO modes. Both standard (11-bit) and extended (29-bit) messaging formats are supported. See section 37, Controller Area Network (CAN) Module in User's Manual.
USB 2.0 Full-Speed Module (USBFS)	Full-Speed USB controller that can operate as a host controller or device controller. The module supports full-speed and low-speed (host controller only) transfer as defined in Universal Serial Bus Specification 2.0. The module has an internal USB transceiver and supports all of the transfer types defined in Universal Serial Bus Specification 2.0. The USB has buffer memory for data transfer, providing a maximum of 10 pipes. Pipes 1 to 9 can be assigned any endpoint number based on the peripheral devices used for communication or based on your system. See section 32, USB 2.0 Full-Speed Module (USBFS) in User's Manual.
USB 2.0 High-Speed Module (USBHS)	High-Speed USB controller that can operate as a host controller or a device controller. As a host controller, the USBHS supports high-speed transfer, full-speed transfer, and low-speed transfer as defined in Universal Serial Bus Specification 2.0. As a device controller, the USBHS supports high-speed transfer and full-speed transfer as defined in Universal Serial Bus Specification 2.0. The USBHS has an internal USB transceiver and supports all of the transfer types defined in Universal Serial Bus Specification 2.0. The USBHS has FIFO buffers for data transfer, providing a maximum of 10 pipes. Any endpoint number can be assigned to pipes 1 to 9, based on the peripheral devices or your system for communication. See section 33, USB 2.0 High-Speed Module (USBHS) in User's Manual.

1.3 Part Numbering

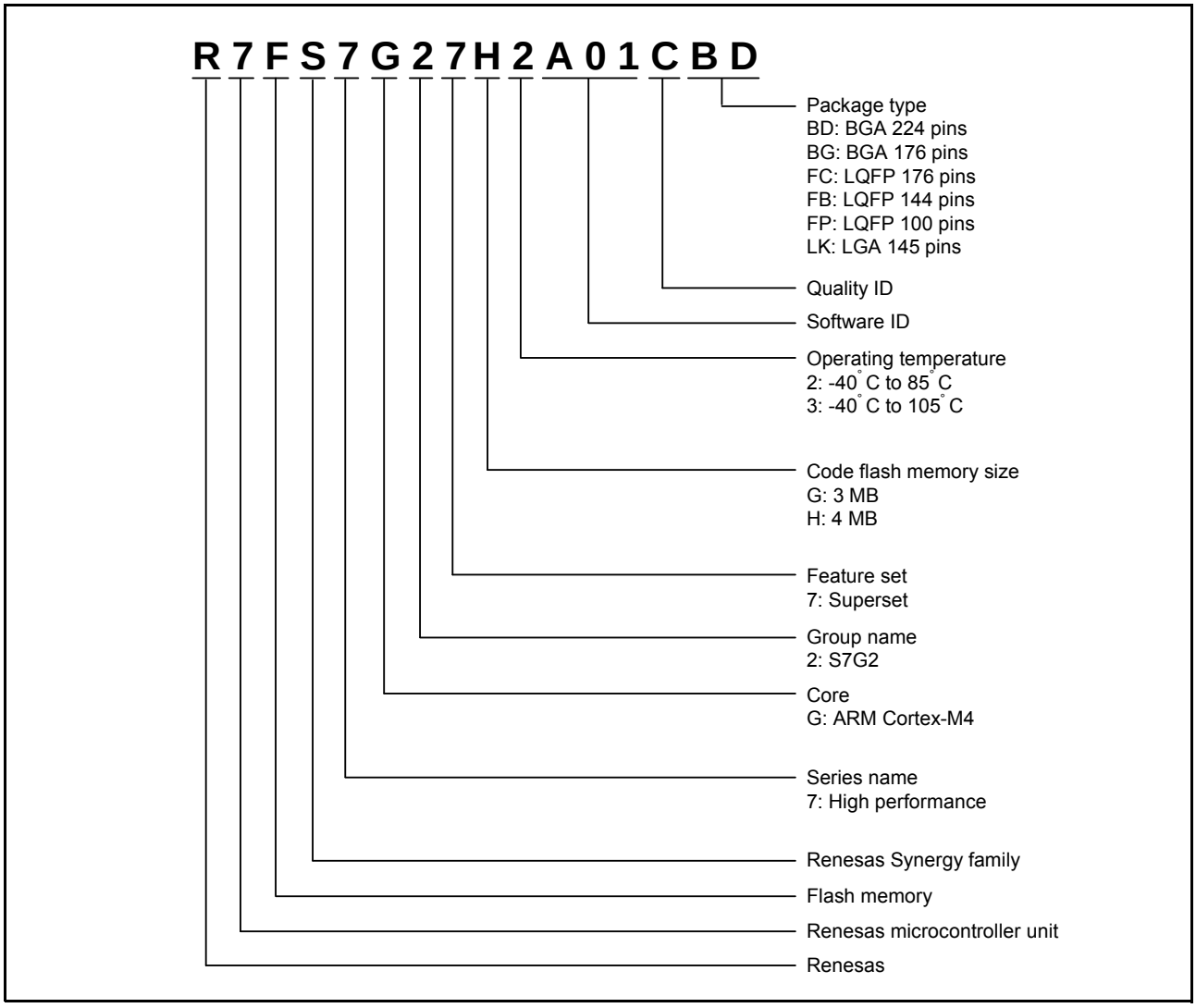


Figure 1.2 Part numbering scheme

1.7 Pin Lists

Table 1.17 Pin list (1/12)

Pin number						Power, System, Clock, Debug,	I/O port	Extbus		Timers				Communication interfaces										Analog		HMI		
BGA224	BGA176	LQFP176	LGA145	LQFP144	LQFP100			External bus	SDRAM	AGT	GPT	GPT	RTC	USBFS, CAN	SCI0,2,4,6,8 (30 MHz)	SCI1,3,5,7,9 (30 MHz)	IIC	SPI, QSPI	SSI	MII (25 MHz)	RMII (50 MHz)	USBHS	SDHI	ADC12	DAC12, ACMPHS	CTSU	Interrupt	GLCDC, PDC
N13	N13	1	N13	1	1	-	P400	-	-	-	-	GTIOC6A_A	-	-	SCK4_B	SCK7_A	SCL0_A	-	AUDIO_CLK	ET1_TX_CLK	-	-	-	ADTRG1_B	-	-	IRQ0	-
P15	R15	2	L11	2	2	-	P401	-	-	-	GETRGA_B	GTIOC6B_A	-	CTX0_B	CTS4_RTS4_B/SS4_B	TXD7_A/MOSI7_A/SDA7_A	SDA0_A	-	-	ET0_MDC	ET0_MDC	-	-	-	-	-	IRQ5-DS	-
N14	P14	3	M13	3	3	-	P402	-	-	AGTIO0_B/AGTIO1_B	-	-	RTCIC0	CRX0_B	-	RXD7_A/MISO7_A/SCL7_A	-	-	-	ET0_MDIO	ET0_MDIO	-	-	-	-	-	IRQ4-DS	-
N15	M12	4	K11	4	4	-	P403	-	-	AGTIO0_C/AGTIO1_C	-	GTIOC3A_B	RTCIC1	-	-	CTS7_RTS7_A/SS7_A	-	-	SSISCK0_A	ET1_MDC	ET1_MDC	-	-	-	-	-	-	PIXD7
K10	M13	5	L12	5	5	-	P404	-	-	-	-	GTIOC3B_B	RTCIC2	-	-	-	-	-	SSIWS0_A	ET1_MDIO	ET1_MDIO	-	-	-	-	-	-	PIXD6
M13	P15	6	L13	6	6	-	P405	-	-	-	-	GTIOC1A_B	-	-	-	-	-	-	SSITXD0_A	ET1_TX_EN	RMII1_TXD_EN	-	-	-	-	-	-	PIXD5
J9	N14	7	J10	7	7	-	P406	-	-	-	-	GTIOC1B_B	-	-	-	-	-	-	SSIRXD0_A	ET1_RX_ER	RMII1_TXD1	-	-	-	-	-	-	PIXD4
M14	N15	8	H10	8	-	-	P700	-	-	-	-	GTIOC5A_B	-	-	-	-	-	-	-	ET1_ETXD1	RMII1_TXD0	-	-	-	-	-	-	PIXD3
M15	M14	9	K12	9	-	-	P701	-	-	-	-	GTIOC5B_B	-	-	-	-	-	-	-	ET1_ETXD0	REF50CK1	-	-	-	-	-	-	PIXD2
K11	L12	10	K13	10	-	-	P702	-	-	-	-	GTIOC6A_B	-	-	-	-	-	-	-	ET1_ERXD1	RMII1_RXD0	-	-	-	-	-	-	PIXD1
J8	M15	11	J11	11	-	-	P703	-	-	-	-	GTIOC6B_B	-	-	-	-	-	-	-	ET1_ERXD0	RMII1_RXD1	-	-	-	-	-	-	PIXD0
J10	L13	12	H11	12	-	-	P704	-	-	-	-	-	-	-	-	-	-	-	-	ET1_RX_CLK	RMII1_RX_ER	-	-	-	-	-	-	HSYNC
L13	K12	13	G11	13	-	-	P705	-	-	-	-	-	-	-	-	-	-	-	-	ET1_CRS	RMII1_CRS_DV	-	-	-	-	-	-	PIXCLK
L14	L14	14	-	-	-	-	P706	-	-	-	-	-	-	-	-	RXD3_B/MISO3_B/SCL3_B	-	-	-	-	-	USBHS_OVRCURB	-	-	-	-	IRQ7	-
L15	L15	15	-	-	-	-	P707	-	-	-	-	-	-	-	-	TXD3_B/MOSI3_B/SDA3_B	-	-	-	-	-	USBHS_OVRCURA	-	-	-	-	IRQ8	-

Table 1.17 Pin list (4/12)

Pin number						Power, System, Clock, Debug,	I/O port	Extbus		Timers				Communication interfaces										Analog		HMI		
BGA224	BGA176	LQFP176	LGA145	LQFP144	LQFP100			External bus	SDRAM	AGT	GPT	GPT	RTC	USBFS, CAN	SCI0,2,4,6,8 (30 MHz)	SCI1,3,5,7,9 (30 MHz)	IIC	SPI, QSPI	SSI	MII (25 MHz)	RMII (50 MHz)	USBHS	SDHI	ADC12	DAC12, ACMPHS	CTSU	Interrupt	GLCDC, PDC
D14	C15	40	D11	32	21	-	P411	-	-	AGTOA1	GTOVUP_B	GTIOC9A_A	-	-	TXD0_B/MOSI0_B/SDA0_B	CTS3_RTS3_A/SS3_A	-	MOSIA_B	-	ET0_ERXD1	RMII0_RXD0	-	SD0DAT0	-	-	TS07	IRQ4	-
C15	C14	41	C12	33	22	-	P410	-	-	AGTOB1	GTOVLO_B	GTIOC9B_A	-	-	RXD0_B/MISO0_B/SCL0_B	SCK3_A	-	MISOA_B	-	ET0_ERXD0	RMII0_RXD1	-	SD0DAT1	-	-	TS06	IRQ5	-
C14	B15	42	B13	34	23	-	P409	-	-	-	GTOWUP_B	GTIOC10A_A	-	USB_EXICEN_A	-	TXD3_A/MOSI3_A/SDA3_A	-	-	-	ET0_RX_CLK	RMII0_RX_ER	USBHS_EXICEN	-	-	-	TS05	IRQ6	-
B15	D13	43	D10	35	24	-	P408	-	-	-	GTOWLO_B	GTIOC10B_A	-	USB_ID_A	-	RXD3_A/MISO3_A/SCL3_A	-	-	-	ET0_CRS	RMII0_CRS_DV	USBHS_ID	-	-	-	TS04	IRQ7	-
A15	A15	44	A13	36	25	-	P407	-	-	-	-	-	RTCOUT	USB_VBUS	CTS4_RTS4_A/SS4_A	-	SDA0_B	SSLB3_A	-	ET0_EXOUT	ET0_EXOUT	-	-	ADTRG0	-	TS03	-	-
B13	C13	45	B11	37	26	VSS_USB	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
B14	B14	46	A12	38	27		-	-	-	-	-	-	-	USB_DM	-	-	-	-	-	-	-	-	-	-	-	-	-	-
A14	A14	47	B12	39	28		-	-	-	-	-	-	-	USB_DP	-	-	-	-	-	-	-	-	-	-	-	-	-	-
A13	B13	48	A11	40	29	VCC_USB	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-	-
C13	C12	49	C11	41	30	-	P207	A17	-	-	-	-	-	-	-	-	-	SSLB2_A	-	-	-	-	-	-	-	TS02	-	-
G9	D12	50	B10	42	31	-	P206	WAIT	-	-	GTIU_A	-	-	USB_VBUSEN_A	RXD4_A/MISO4_A/SCL4_A	-	SDA1_A	SSLB1_A	SSIDATA1_A	ET0_LINKSTA	ET0_LINKSTA	-	SD0DAT2	-	-	TS01	IRQ0-DS	-
C12	E12	51	A10	43	32	CLKOUT_A	P205	A16	-	AGTO1	GTIV_A	GTIOC4A_B	-	USB_OVRCURA_A-DS	TXD4_A/MOSI4_A/SDA4_A	CTS9_RTS9_A/SS9_A	SCL1_A	SSLB0_A	SSIWS1_A	ET0_WOL	ET0_WOL	-	SD0DAT3	-	-	TSCAP_A	IRQ1-DS	-
D11	A13	52	C10	44	-	CACREF_A	P204	A18	-	AGTIO1_A	GTIW_A	GTIOC4B_B	-	USB_OVRCURB_A-DS	SCK4_A	SCK9_A	SCL0_B	RSPCKB_A	SSISCK1_A	ET0_RX_DV	-	-	SD0DAT4	-	-	TS00	-	-
B12	D11	53	A9	45	-	-	P203	A19	-	-	-	GTIOC5A_A	-	CTX0_A	CTS2_RTS2_A/SS2_A	TXD9_A/MOSI9_A/SDA9_A	-	MOSIB_A	-	ET0_COL	-	-	SD0DAT5	-	-	TSCAP_B	IRQ2-DS	-

Table 2.13 Clock timing except for sub-clock oscillator (2/2)

Item		Symbol	Min	Typ	Max	Unit	Test conditions
HOCO clock oscillator oscillation frequency	Without FLL	f_{HOCO16}	15.61	16	16.39	MHz	–20 ≤ Ta ≤ 105°C
		f_{HOCO18}	17.56	18	18.44		
		f_{HOCO20}	19.52	20	20.48		
		f_{HOCO16}	15.52	16	16.48		–40 ≤ Ta ≤ –20°C
		f_{HOCO18}	17.46	18	18.54		
		f_{HOCO20}	19.40	20	20.60		
	With FLL	f_{HOCO16}	15.91	16	16.09		SOSC frequency is 32.768kHz ± 50ppm
		f_{HOCO18}	17.90	18	18.10		
		f_{HOCO20}	19.89	20	20.11		
HOCO clock oscillation stabilization wait time *2		t_{HOCOWT}	-	-	64.7	µs	-
FLL stabilization wait time		t_{FLLWT}	-	-	3	ms	-
PLL clock frequency		f_{PLL}	120	-	240	MHz	-
PLL clock oscillation stabilization wait time		t_{PLLWT}	-	-	174.9	µs	Figure 2.7

Note 1. When setting up the main clock oscillator, ask the oscillator manufacturer for an oscillation evaluation and use the results as the recommended oscillation stabilization time. Set the MOSCWTCR register to a value equal to or greater than the recommended value.
After changing the setting in the MOSCCR.MOSTP bit to start main clock operation, read the OSCSF.MOSCSF flag to confirm that it is 1, and then start using the main clock oscillator.

Note 2. This is the time from release from reset state until the HOCO oscillation frequency (fHOCO) reaches the range for guaranteed operation.

Table 2.14 Clock timing for the sub-clock oscillator

Item	Symbol	Min	Typ	Max	Unit	Test conditions
Sub-clock frequency	f_{SUB}	-	32.768	-	kHz	-
Sub-clock oscillation stabilization wait time	$t_{SUBOSCWT}$	-	-	-*1	s	-

Note 1. When setting up the sub-clock oscillator, ask the oscillator manufacturer for an oscillation evaluation and use the results as the recommended oscillation stabilization time.
After changing the setting in the SOSCCR.SOSTP bit to start sub-clock operation, only start using the sub-clock oscillator after the sub-clock oscillation stabilization time elapses with an adequate margin. Two times the value shown is recommended.

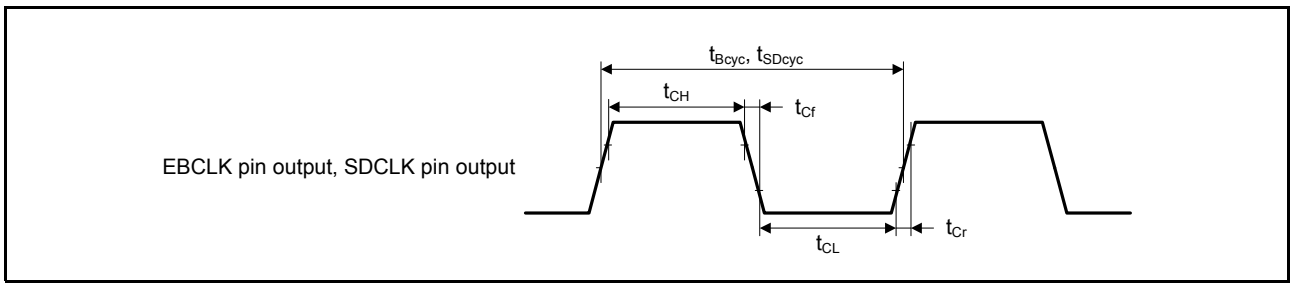


Figure 2.3 EBCLK and SDCLK output timing

2.3.4 Wakeup Timing and Duration

Table 2.16 Timing of recovery from low-power modes and duration

Item			Symbol	Min	Typ	Max	Unit	Test conditions
Recovery time from Software Standby mode*1	Crystal resonator connected to main clock oscillator	System clock source is main clock oscillator*2	t_{SBYMC}	-	-	2.8	ms	Figure 2.10 The division ratio of all oscillators is 1.
		System clock source is PLL with main clock oscillator*3	t_{SBYPC}	-	-	3.2	ms	
	External clock input to main clock oscillator	System clock source is main clock oscillator*4	t_{SBYEX}	-	-	280	µs	
		System clock source is PLL with main clock oscillator*5	t_{SBYPE}	-	-	700	µs	
	System clock source is sub-clock oscillator*8		t_{SBYSC}	-	-	1.3	ms	
	System clock source is LOCO*8		t_{SBYLO}	-	-	1.4	ms	
	System clock source is HOCO clock oscillator*6		t_{SBYHO}	-	-	300	µs	
	System clock source is MOCO clock oscillator*7		t_{SBYMO}	-	-	300	µs	
Recovery time from Deep Software Standby mode			t_{DSBY}	-	-	1.0	ms	Figure 2.11
Wait time after cancellation of Deep Software Standby mode			t_{DSBYWT}	31	-	32	t_{cyc}	
Recovery time from Software Standby mode to Snooze	High-speed mode when system clock source is HOCO (20 MHz)		t_{SNZ}	-	-	68	µs	-
	High-speed mode when system clock source is MOCO (8 MHz)		t_{SNZ}	-	-	14*9	µs	
Normal mode duration*10	System clock source is main clock oscillator		t_{NML}	-*11	-	-	$t_{cycmosc}$	Figure 2.10
	System clock source is PLL with main clock oscillator							

Note 1. The recovery time is determined by the system clock source. When multiple oscillators are active, the recovery time can be determined with the following equation:
Total recovery time = recovery time for an oscillator as the system clock source + the longest oscillation stabilization time of any oscillators requiring longer stabilization times than the system clock source + 2 LOCO cycles (when LOCO is operating) + 3 SOSC cycles (when Subosc is oscillating and MSTPC0 = 0 (CAC module stop)).

Note 2. When the frequency of the crystal is 24 MHz (Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 05h). For other settings (MOSCWTCR is set to Xh), the recovery time can be determined with the following equation:
t_{SBYMC} (MOSCWTCR = Xh) = t_{SBYMC} (MOSCWTCR = 05h) + ($t_{MAINOSCWT}$ (MOSCWTCR = Xh) - $t_{MAINOSCWT}$ (MOSCWTCR = 05h))

Note 3. When the frequency of PLL is 240 MHz (Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 05h). For other settings (MOSCWTCR is set to Xh), the recovery time can be determined with the following equation:
t_{SBYMC} (MOSCWTCR = Xh) = t_{SBYMC} (MOSCWTCR = 05h) + ($t_{MAINOSCWT}$ (MOSCWTCR = Xh) - $t_{MAINOSCWT}$ (MOSCWTCR = 05h))

Note 4. When the frequency of the external clock is 24 MHz (Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 00h). For other settings (MOSCWTCR is set to Xh), the recovery time can be determined with the following equation:
t_{SBYMC} (MOSCWTCR = Xh) = t_{SBYMC} (MOSCWTCR = 00h) + ($t_{MAINOSCWT}$ (MOSCWTCR = Xh) - $t_{MAINOSCWT}$ (MOSCWTCR = 00h))

Note 5. When the frequency of PLL is 240 MHz (Main Clock Oscillator Wait Control Register (MOSCWTCR) is set to 00h). For other settings (MOSCWTCR is set to Xh), the recovery time can be determined with the following

equation:
t_{SBYMC} (MOSCWTCR = Xh) = t_{SBYMC} (MOSCWTCR = 00h) + ($t_{MAINOSCWT}$ (MOSCWTCR = Xh) - $t_{MAINOSCWT}$ (MOSCWTCR = 00h))

Note 6. The HOCO frequency is 20 MHz.

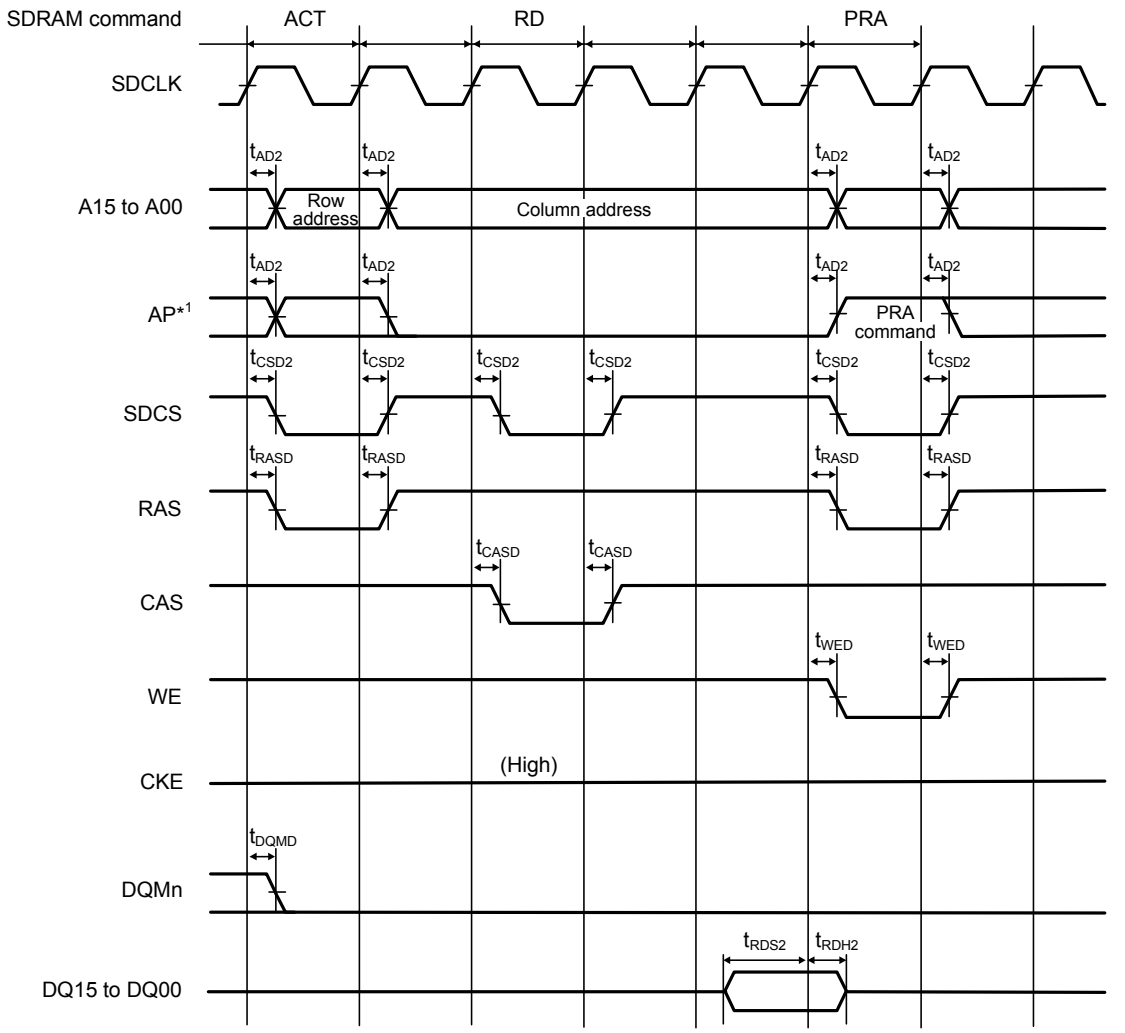
Note 7. The MOCO frequency is 8 MHz.

Note 8. In Subosc-speed mode, the sub-clock oscillator or LOCO continues oscillating in Software Standby mode.

Note 9. When the SNZCR.RXDREQEN bit is set to 0, 86 µs is added as the power supply recovery time.

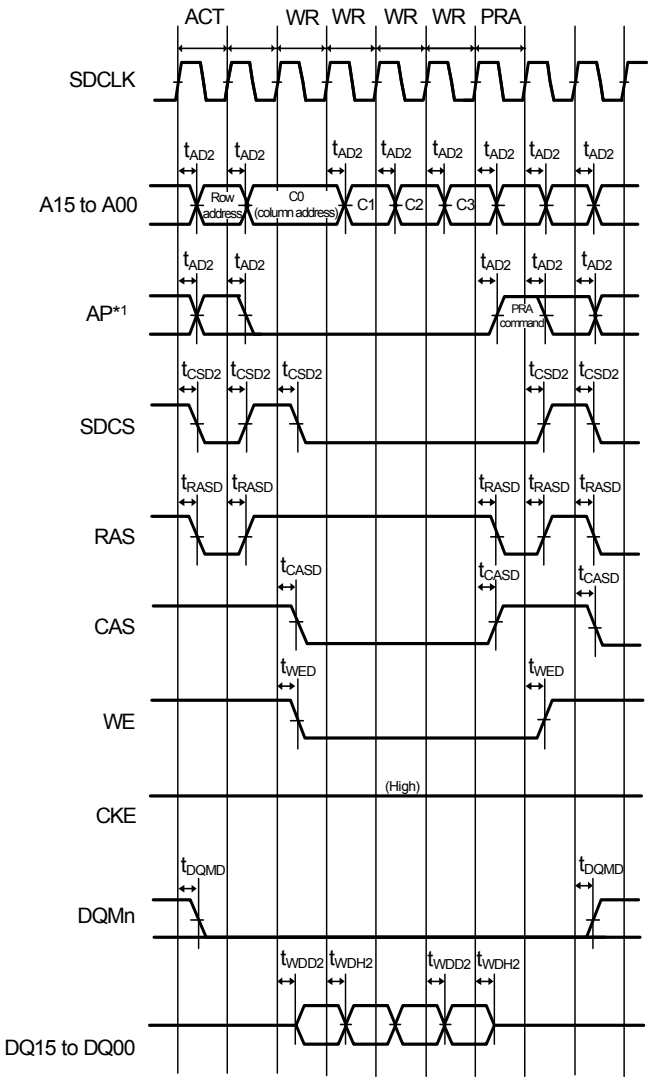
Note 10. This defines the duration of Normal mode after a transition from Snooze to Normal mode.
The following cases are valid uses of the main clock oscillator:
- The crystal resonator is connected to main clock oscillator
- The external clock is input to main clock oscillator.
The following cases are excluded:
- The main clock resonator is not connected to the system clock source
- Transition is made from Software Standby to Normal mode.

Note 11. The same value as set in MOSCWTCR.MSTS[3:0]. Duration of Normal mode must be longer than the main clock oscillator wait time.
MOSCWTCR: Main Clock Oscillator Wait Control Register
$t_{cycmosc}$: Main clock oscillator frequency cycle.



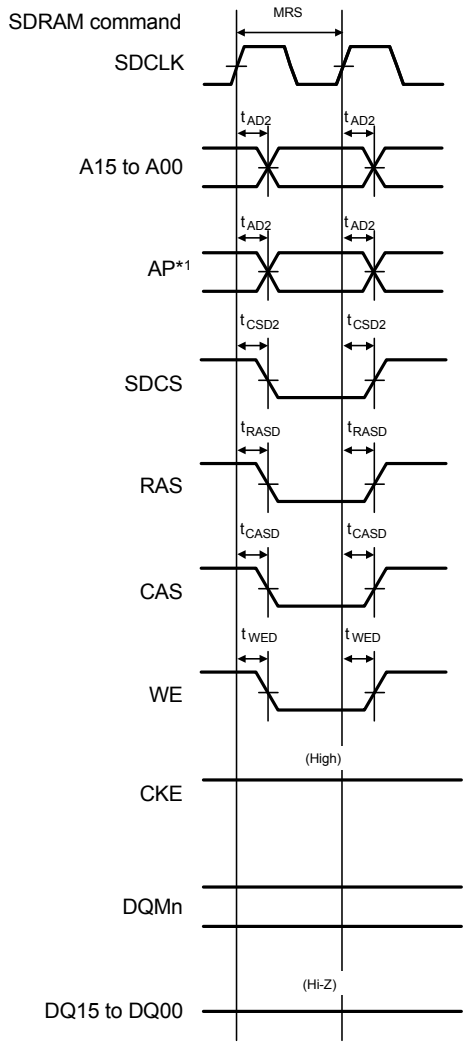
Note 1. Address pins are for output of the precharge-select command (Precharge-sel) for the SDRAM.

Figure 2.19 SDRAM single read timing



Note 1. Address pins are for output of the precharge-select command (Precharge-sel) for the SDRAM.

Figure 2.22 SDRAM multiple write timing



Note 1. Address pins are for output of the precharge-select command (Precharge-sel) for the SDRAM.

Figure 2.24 SDRAM mode register set timing

Note 1. t_{PBcyc}: PCLKB cycle.
Note 2. t_{cac}: CAC count clock source cycle.

2.3.10 SCI Timing

Table 2.22 SCI timing (1)
Conditions: High drive output is selected in the port drive capability bit in the PmnPFS register for the following pins: SCK0 to SCK9 (except for SCK4_B, SCK7_A), SCK4_B, SCK7_A.
For other pins, middle drive output is selected in the port drive capability bit in the PmnPFS register.

Item			Symbol	Min	Max	Unit*1	Test conditions
SCI	Input clock cycle	Asynchronous	t_{Scyc}	4	-	t_{Pcyc}	Figure 2.35
		Clock synchronous		6	-		
	Input clock pulse width		t_{SCKW}	0.4	0.6	t_{Scyc}	
	Input clock rise time		t_{SCKr}	-	5	ns	
	Input clock fall time		t_{SCKf}	-	5	ns	
	Output clock cycle	Asynchronous	t_{Scyc}	6	-	t_{Pcyc}	
		Clock synchronous		4	-		
	Output clock pulse width		t_{SCKW}	0.4	0.6	t_{Scyc}	
	Output clock rise time		t_{SCKr}	-	5	ns	
	Output clock fall time		t_{SCKf}	-	5	ns	
	Transmit data delay	Clock synchronous	t_{TXD}	-	25	ns	Figure 2.36
	Receive data setup time	Clock synchronous	t_{RXS}	15	-	ns	
	Receive data hold time	Clock synchronous	t_{RXH}	5	-	ns	

Note 1. t_{Pcyc}: PCLKA cycle.

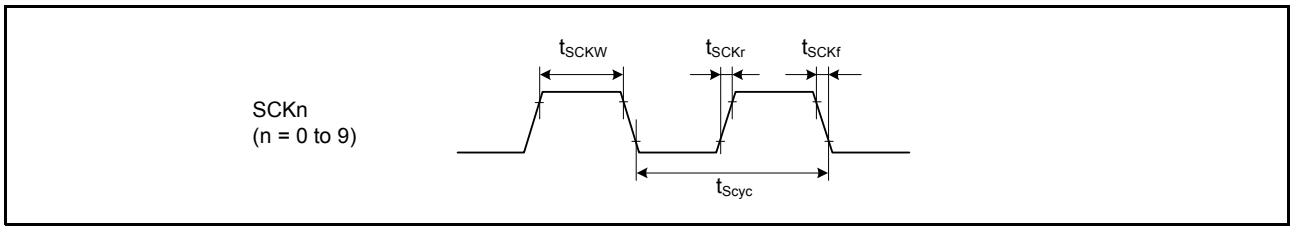


Figure 2.35 SCK clock input/output timing

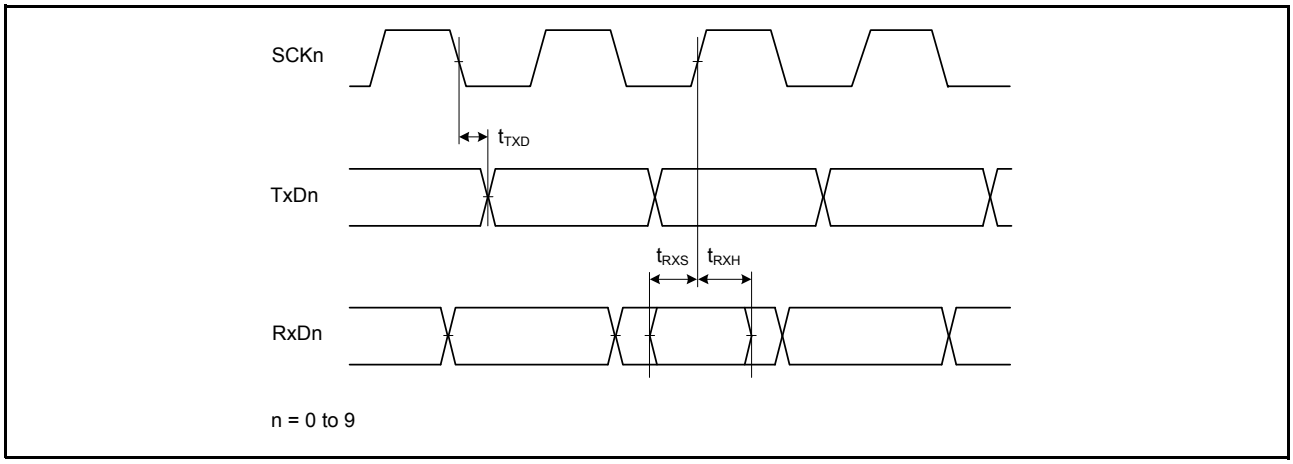


Figure 2.36 SCI input/output timing in clock synchronous mode

Table 2.23 SCI timing (2)

Conditions: High drive output is selected in the port drive capability bit in the PmnPFS register for the following pins: SCK0 to SCK9 (except for SCK4_B, SCK7_A).
For the SCK4_B and SCK7_A pins, middle drive output is selected in the port drive capability bit in the PmnPFS register.
For the MISO1_A pins, low drive output is selected in the port drive capability bit in the PmnPFS register.
For other pins, middle drive output is selected in the port drive capability bit in the PmnPFS register.

Item		Symbol	Min	Max	Unit	Test conditions
Simple SPI	SCK clock cycle output (master)	t_{SPcyc}	4 (PCLKA ≤ 60 MHz) 8 (PCLKA > 60 MHz)	65536	t_{Pcyc}	Figure 2.37
	SCK clock cycle input (slave)	-	6 (PCLKA ≤ 60 MHz) 12 (PCLKA > 60 MHz)	65536		
	SCK clock high pulse width	t_{SPCKWH}	0.4	0.6	t_{SPcyc}	
	SCK clock low pulse width	t_{SPCKWL}	0.4	0.6	t_{SPcyc}	
	SCK clock rise and fall time	t_{SPCKr}, t_{SPCKf}	-	20	ns	
	Data input setup time	t_{SU}	33.3	-	ns	Figure 2.38 to Figure 2.41
	Data input hold time	t_{H}	33.3	-	ns	
	SS input setup time	t_{LEAD}	1	-	t_{SPcyc}	
	SS input hold time	t_{LAG}	1	-	t_{SPcyc}	
	Data output delay	t_{OD}	-	33.3	ns	
	Data output hold time	t_{OH}	–10	-	ns	
	Data rise and fall time	t_{Dr}, t_{Df}	-	16.6	ns	
	SS input rise and fall time	t_{SSLr}, t_{SSLf}	-	16.6	ns	
	Slave access time	t_{SA}	-	4 (PCLKA ≤ 60 MHz) 8 (PCLKA > 60 MHz)	t_{Pcyc}	Figure 2.41
	Slave output release time	t_{REL}	-	5 (PCLKA ≤ 60 MHz) 10 (PCLKA > 60 MHz)	t_{Pcyc}	

Note: MISO1_A is not supported in these specifications.

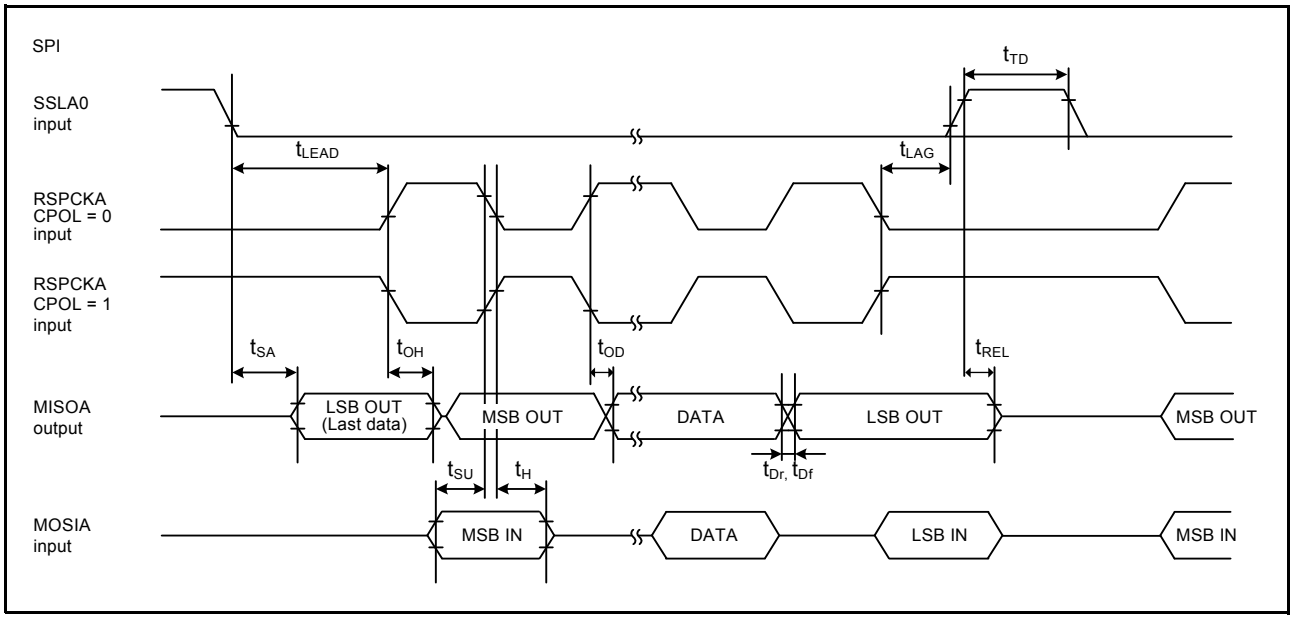


Figure 2.49 SPI timing for slave when CPHA = 1

2.3.12 QSPI Timing

Table 2.26 QSPI timing
Conditions: High drive output is selected in the port drive capability bit in the PmnPFS register.

Item		Symbol	Min	Max	Unit*1	Test conditions
QSPI	QSPCK clock cycle	t_{QScyc}	2	48	t_{Pcyc}	Figure 2.50
	QSPCK clock high pulse width	t_{QSWH}	t_{QScyc} × 0.4	-	ns	
	QSPCK clock low pulse width	t_{QSWL}	t_{QScyc} × 0.4	-	ns	
	Data input setup time	t_{Su}	11	-	ns	Figure 2.51
	Data input hold time	t_{IH}	0	-	ns	
	QSSL setup time	t_{LEAD}	(N+0.5) x t_{Qscyc} - 5 *2	(N+0.5) x t_{Qscyc} +100 *2	ns	
	QSSL hold time	t_{LAG}	(N+0.5) x t_{Qscyc} - 5 *3	(N+0.5) x t_{Qscyc} +100 *3	ns	
	Data output delay	t_{OD}	-	4	ns	
	Data output hold time	t_{OH}	–3.3	-	ns	
	Successive transmission delay	t_{TD}	1	16	t_{QScyc}	

Note 1. t_{Pcyc}: PCLKA cycle.
Note 2. N is set to 0 or 1 in SFMSLD.
Note 3. N is set to 0 or 1 in SFMSHD.

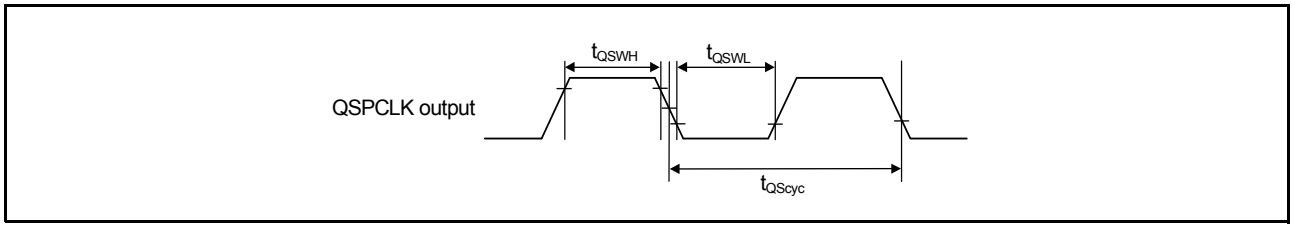


Figure 2.50 QSPI clock timing

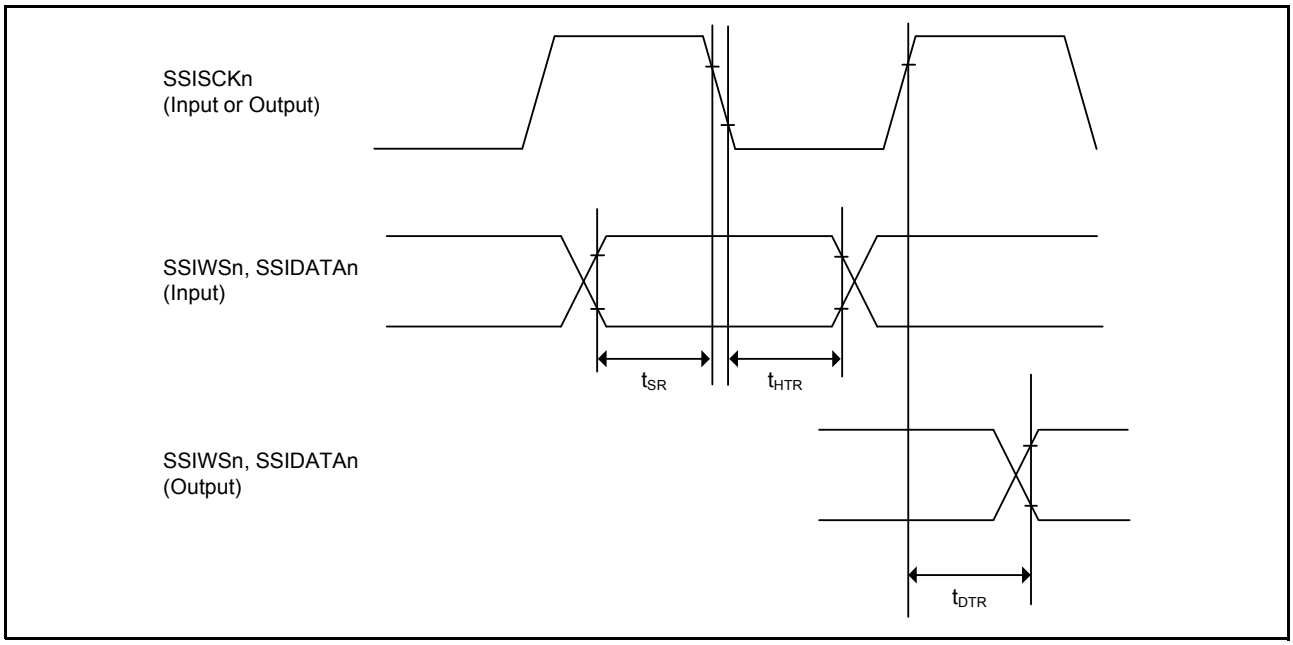


Figure 2.55 SSI data transmit and receive timing when SSICR.SCKP = 1

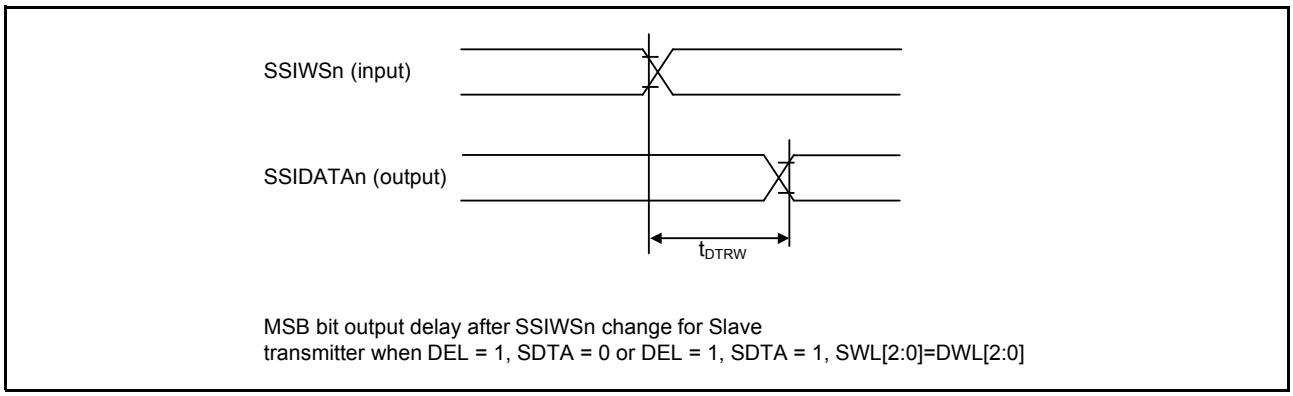


Figure 2.56 SSI data output delay after SSIWSn change

2.3.15 SD/MMC Host Interface Timing

Table 2.30 SD/MMC Host Interface signal timing
Conditions: High drive output is selected in the port drive capability bit in the PmnPFS register.
Clock duty ratio is 50%.

Item	Symbol	Min	Max	Unit	Test conditions
SDCLK clock cycle	T_{SDCYC}	20	-	ns	Figure 2.57
SDCLK clock high pulse width	T_{SDWH}	6.5	-	ns	
SDCLK clock low pulse width	T_{SDWL}	6.5	-	ns	
SDCLK clock rise time	T_{SDLH}	-	3	ns	
SDCLK clock fall time	T_{SDHL}	-	3	ns	
SDCMD/SDDAT output data delay	T_{SDODLY}	–6	5	ns	
SDCMD/SDDAT input data setup	T_{SDIS}	4	-	ns	
SDCMD/SDDAT input data hold	T_{SDIH}	2	-	ns	

2.3.17 PDC Timing

Table 2.32 PDC timing
Conditions: Middle drive output is selected in the port drive capability bit in the PmnPFS register.
Output load conditions: V_{OH} = VCC × 0.5, V_{OL} = VCC × 0.5, C = 30 pF

Item		Symbol	Min	Max	Unit	Test conditions
PDC	PIXCLK input cycle time	t_{PIXcyc}	37	-	ns	Figure 2.68
	PIXCLK input high pulse width	t_{PIXH}	10	-	ns	
	PIXCLK input low pulse width	t_{PIXL}	10	-	ns	
	PIXCLK rise time	t_{PIXr}	-	5	ns	
	PIXCLK fall time	t_{PIXf}	-	5	ns	
	PCKO output cycle time	t_{PCKcyc}	2 × t_{PBcyc}	-	ns	Figure 2.69
	PCKO output high pulse width	t_{PCKH}	(t_{PCKcyc} – t_{PCKr} – t_{PCKf})/2 – 3	-	ns	
	PCKO output low pulse width	t_{PCKL}	(t_{PCKcyc} – t_{PCKr} – t_{PCKf})/2 – 3	-	ns	
	PCKO rise time	t_{PCKr}	-	5	ns	
	PCKO fall time	t_{PCKf}	-	5	ns	
	VSYNV/HSYNC input setup time	t_{SYNCS}	10	-	ns	Figure 2.70
	VSYNV/HSYNC input hold time	t_{SYNCH}	5	-	ns	
	PIXD input setup time	t_{PIXDS}	10	-	ns	
	PIXD input hold time	t_{PIXDH}	5	-	ns	

Note 1. t_{PBcyc}: PCLKB cycle.

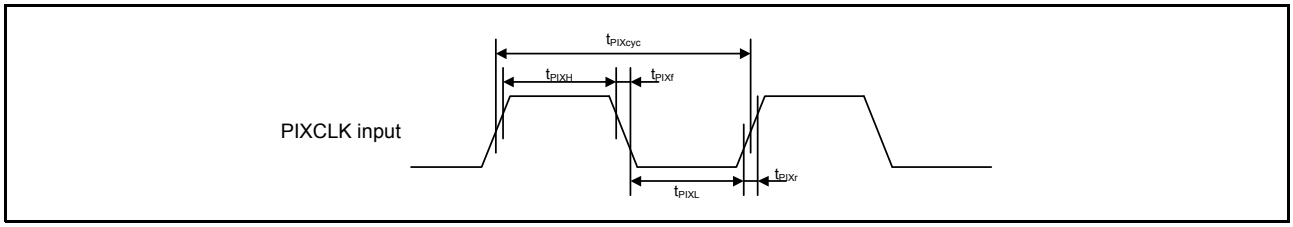


Figure 2.68 PDC input clock timing

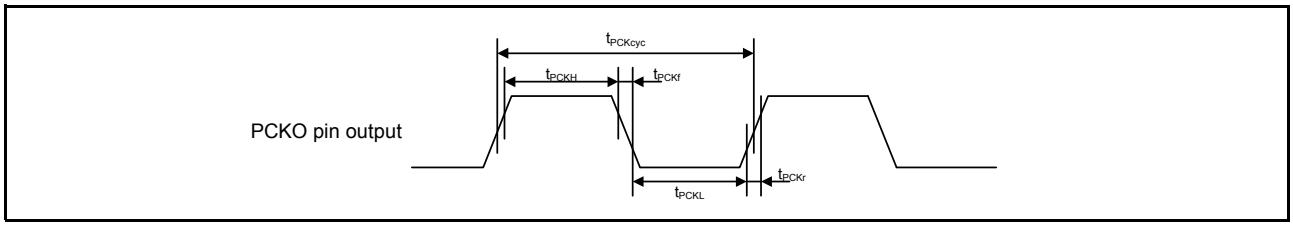


Figure 2.69 PDC output clock timing

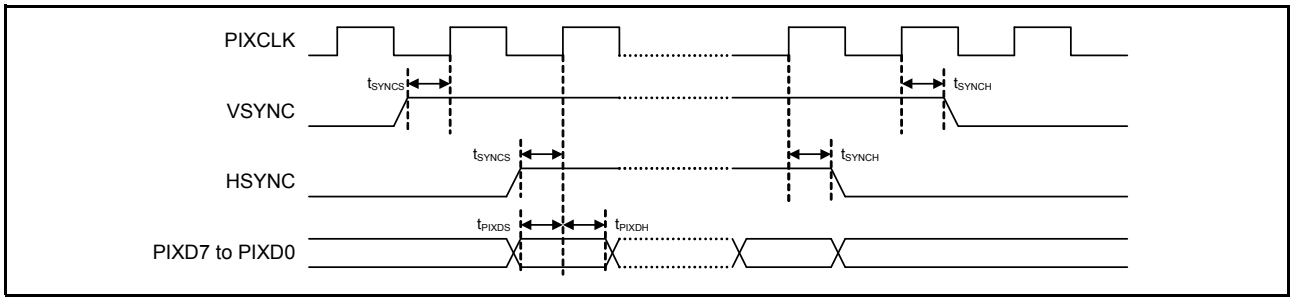


Figure 2.70 PDC AC timing

2.3.18 Graphics LCD Controller Timing

Table 2.33 Graphics LCD Controller timing
Conditions:
LCD_CLK: High drive output is selected in the port drive capability bit in the PmnPFS register.
LCD_DATA: Middle drive output is selected in the port drive capability bit in the PmnPFS register.

Item		Symbol	Min	Typ	Max	Unit	Test conditions
LCD_EXTCLK input clock frequency		t_{Ecyc}	-	-	60*1	MHz	Figure 2.71
LCD_EXTCLK input clock low pulse width		t_{WL}	0.45	-	0.55	t_{Ecyc}	
LCD_EXTCLK input clock high pulse width		t_{WH}	0.45	-	0.55		
LCD_CLK output clock frequency		t_{Lcyc}	-	-	60*1	MHz	Figure 2.72
LCD_CLK output clock low pulse width		t_{LOL}	0.4	-	0.6	t_{Lcyc}	Figure 2.72
LCD_CLK output clock high pulse width		t_{LOH}	0.4	-	0.6	t_{Lcyc}	Figure 2.72
LCD data output delay timing	_A or _B combinations*2	t_{DD}	–3.5	-	4	ns	Figure 2.73
	_A and _B combinations*3		–5.0	-	5.5		
LCD data output rise time (0.8 to 2.0 V)		t_{Dr}	-	-	2		Figure 2.74
LCD data output fall time (2.0 to 0.8 V)		t_{Df}	-	-	2		

Note 1. Parallel RGB888, 666,565: Maximum 54 MHz
Serial RGB888: Maximum 60 MHz (4x speed)
Note 2. Use pins that have a letter appended to their names, for instance, “_A” or “_B”, to indicate
Note 3. Pins of group“_A” and “_B” combinations are used.

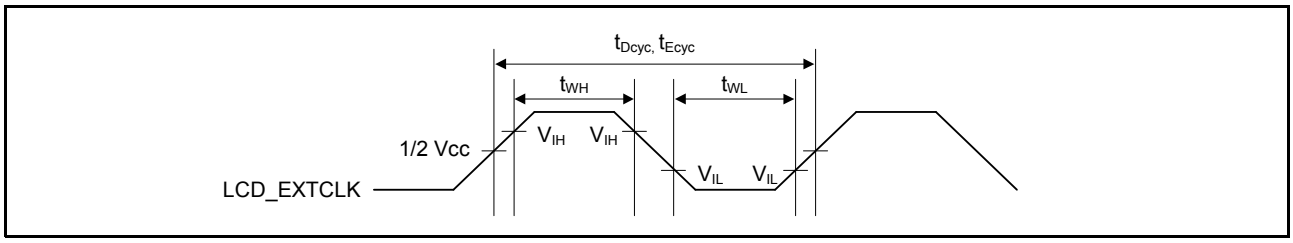


Figure 2.71 LCD_EXTCLK clock input timing

Table 2.40 A/D conversion characteristics for unit 0 (2/2)
Conditions: PCLKC = 1 to 60 MHz

Item			Min	Typ	Max	Unit	Test conditions
Channel-dedicated sample-and-hold circuits in use (AN000 to AN002)	Conversion time*1 (operation at PCLKC = 60 MHz)	Permissible signal source impedance Max. = 1 kΩ	1.06 (0.4 + 0.25)*2	-	-	µs	• Sampling of channel-dedicated sample-and-hold circuits in 24 states • Sampling in 15 states
	Offset error		-	±1.5	±3.5	LSB	AN000 to AN002 = 0.25 V
	Full-scale error		-	±1.5	±3.5	LSB	AN000 to AN002 = VREFH0- 0.25 V
	Absolute accuracy		-	±2.5	±5.5	LSB	-
	DNL differential nonlinearity error		-	±1.0	±2.0	LSB	-
	INL integral nonlinearity error		-	±1.5	±3.0	LSB	-
	Holding characteristics of sample-and hold circuits		-	-	20	µs	-
	Dynamic range		0.25	-	VREFH 0 –0.25	V	-
Channel-dedicated sample-and-hold circuits not in use (AN000 to AN002)	Conversion time*1 (operation at PCLKC = 60 MHz)	Permissible signal source impedance Max. = 1 kΩ	0.88 (0.667)*2	-	-	µs	Sampling in 40 states
	Offset error		-	±1.0	±2.5	LSB	-
	Full-scale error		-	±1.0	±2.5	LSB	-
	Absolute accuracy		-	±2.0	±4.5	LSB	-
	DNL differential nonlinearity error		-	±0.5	±1.5	LSB	-
	INL integral nonlinearity error		-	±1.0	±2.5	LSB	-
High-precision channels (AN003 to AN006)	Conversion time*1 (operation at PCLKC = 60 MHz)	Permissible signal source impedance Max. = 1 kΩ	0.48 (0.267)*2	-	-	µs	Sampling in 16 states
		Max. = 300Ω	0.40 (0.183)*2	-	-	µs	Sampling in 11 states VCC = AVCC0 = 3.0 to 3.6 V 3.0 V ≤ VREFH0 ≤ AVCC0
	Offset error		-	±1.0	±2.5	LSB	-
	Full-scale error		-	±1.0	±2.5	LSB	-
	Absolute accuracy		-	±2.0	±4.5	LSB	-
	DNL differential nonlinearity error		-	±0.5	±1.5	LSB	-
	INL integral nonlinearity error		-	±1.0	±2.5	LSB	-
Normal-precision channels (AN016 to AN021)	Conversion time*1 (Operation at PCLKC = 60 MHz)	Permissible signal source impedance Max. = 1 kΩ	0.88 (0.667)*2	-	-	µs	Sampling in 40 states
	Offset error		-	±1.0	±5.5	LSB	-
	Full-scale error		-	±1.0	±5.5	LSB	-
	Absolute accuracy		-	±2.0	±7.5	LSB	-
	DNL differential nonlinearity error		-	±0.5	±4.5	LSB	-
	INL integral nonlinearity error		-	±1.0	±5.5	LSB	-

Note: These specification values apply when there is no access to the external bus during A/D conversion. If access occurs during A/D conversion, values might not fall within the indicated ranges.
Note 1. The conversion time includes the sampling and comparison times. The number of sampling states is indicated for the test conditions.
Note 2. Values in parentheses indicate the sampling time.

Table 2.41 A/D conversion characteristics for unit 1 (1/2)
Conditions: PCLKC = 1 to 60 MHz

Item	Min	Typ	Max	Unit	Test conditions
Frequency	1	-	60	MHz	-
Analog input capacitance	-	-	30	pF	-

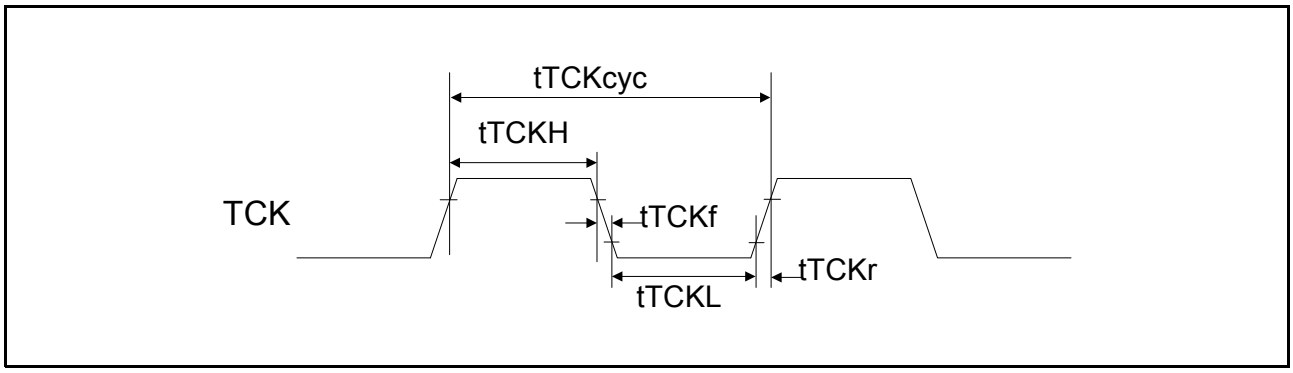


Figure 2.98 JTAG TCK timing

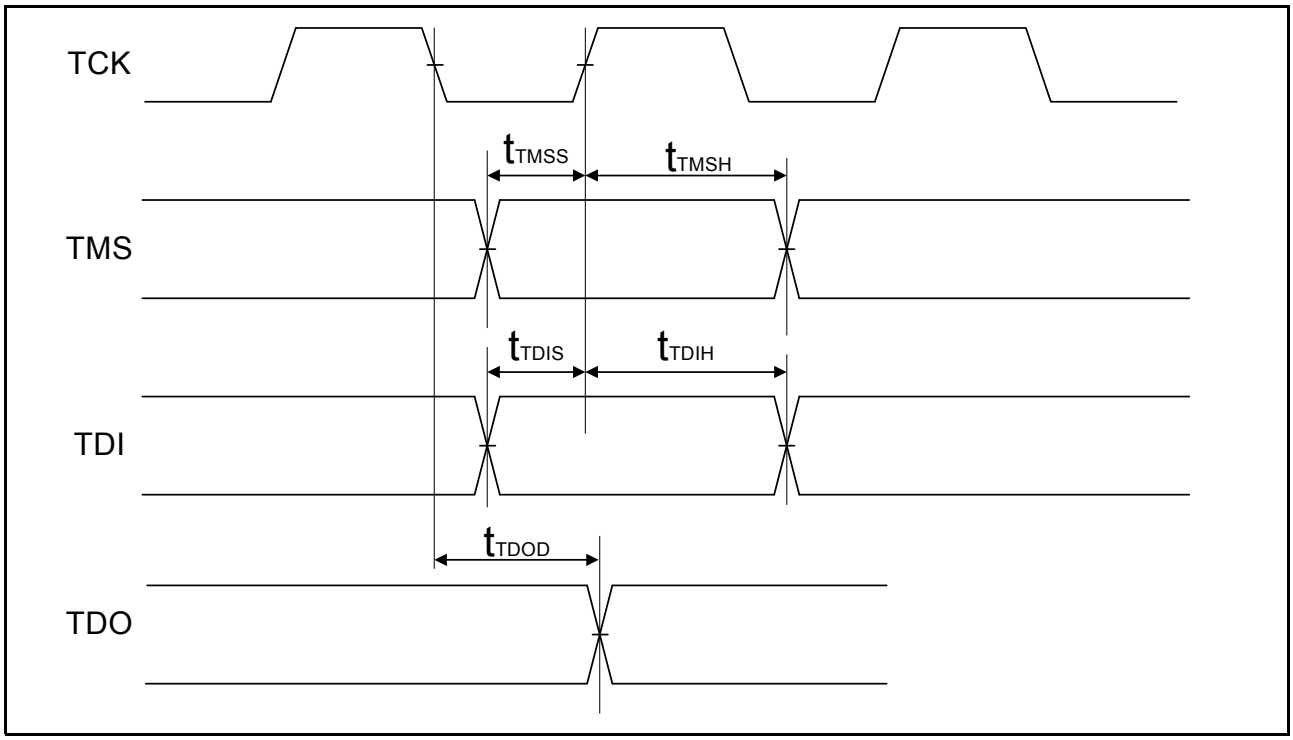


Figure 2.99 JTAG input/output timing

2.17 Serial Wire Debug (SWD)

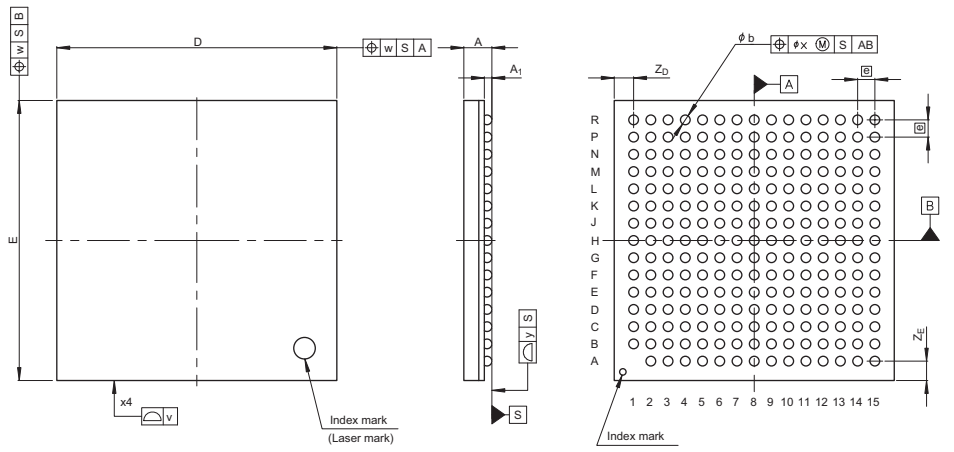
Table 2.56 SWD

Item	Symbol	Min	Typ	Max	Unit	Test conditions
SWCLK clock cycle time	$t_{SWCKcyc}$	40	-	-	ns	Figure 2.100
SWCLK clock high pulse width	t_{SWCKH}	15	-	-	ns	
SWCLK clock low pulse width	t_{SWCKL}	15	-	-	ns	
SWCLK clock rise time	t_{SWCKr}	-	-	5	ns	
SWCLK clock fall time	t_{SWCKf}	-	-	5	ns	
SWDIO setup time	t_{SWDS}	8	-	-	ns	Figure 2.101
SWDIO hold time	t_{SWDH}	8	-	-	ns	
SWDIO data delay time	t_{SWDD}	2	-	28	ns	

Appendix 1. Package Dimensions

For information on the latest version of the package dimensions or mountings, go to “Packages” on the Renesas Electronics Corporation website.

JEITA Package Code	RENESAS Code	Previous Code	MASS[Typ.]
P-LFBGA224-13x13-0.80	PLBG0224GA-A	224FHE	0.4g



Reference Symbol	Dimension in Millimeters		
	Min	Nom	Max
D	—	13.0	—
E	—	13.0	—
v	—	—	0.15
w	—	—	0.20
A	—	—	1.4
A_1	0.3	0.35	0.4
e	—	0.8	—
b	0.4	0.45	0.5
x	—	—	0.08
y	—	—	0.10
Z_D	—	0.9	—
Z_E	—	0.9	—

Figure 1.1 224-pin BGA